

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10565863	TAKAISHI, YOSHITOMO
	<b>Examiner</b>	<b>Art Unit</b>
	JOHN W LEE	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	132	6/3/2009	John W. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor Search	6/3/2009	John W. Lee
EAST Search	6/3/2009	John W. Lee
IEEE Search	6/3/2009	John W. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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